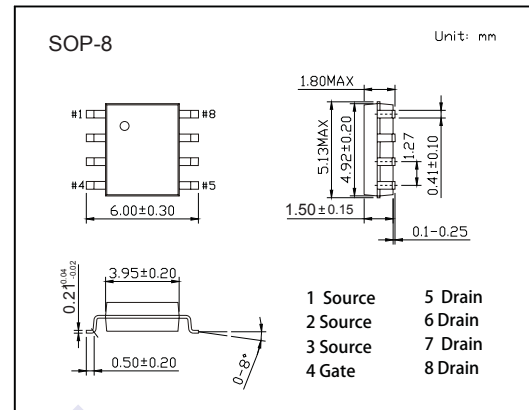
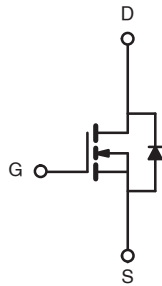


## N-Channel MOSFET

## 2KK7006

## ■ Features

- $V_{DS} = 100\text{ V}$
- $I_D$  (at  $V_{GS} = 10\text{ V}$ ) = 13.5 A
- $R_{DS(ON)}$  (at  $V_{GS} = 10\text{ V}$ ) < 8.3 m $\Omega$
- $R_{DS(ON)}$  (at  $V_{GS} = 4.5\text{ V}$ ) < 10.6 m $\Omega$

■ Absolute Maximum Ratings ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current	$I_D$	$T_A=25^\circ\text{C}$	13.5
		$T_A=70^\circ\text{C}$	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	55	A
Avalanche Current <sup>C</sup>	$I_{AS}$	33	
Avalanche Energy $L = 0.1\text{ mH}$ <sup>C</sup>	$E_{AS}$	54	mJ
$V_{DS}$ Spike	$V_{SPIKE}$	120	V
Power Dissipation <sup>B</sup>	$P_D$	$T_A=25^\circ\text{C}$	3.1
		$T_A=70^\circ\text{C}$	
Thermal Resistance, Junction- to-Ambient <sup>A</sup>	$R_{\theta JA}$	$t \leq 10\text{ s}$	40
Thermal Resistance, Junction- to-Ambient <sup>A D</sup>		Steady-State	75
Thermal Resistance, Junction- to-Lead		Steady-State	24
Junction Temperature	$T_J$	150	$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$	-55 to 150	

Notes:

- The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.
- The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^\circ\text{C}$ , using  $\leq 10\text{ s}$  junction-to-case thermal resistance.
- Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$
- The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and case to ambient.
- The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.
- These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz Copper, assuming a maximum junction temperature of  $T_{J(MAX)}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

## N-Channel MOSFET

## 2KK7006

■ Electrical Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250 \mu\text{A}$ , $V_{GS} = 0\text{V}$	100			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 100\text{V}$ , $V_{GS} = 0\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 100\text{V}$ , $V_{GS} = 0\text{V}$ , $T_J = 55^\circ\text{C}$			5	
Gate to Source Leakage Current	$I_{GSS}$	$V_{DS} = 0\text{V}$ , $V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
Gate to Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$	1.3		2.3	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{V}$ , $I_D = 13.5\text{A}$			8.3	m $\Omega$
		$V_{GS} = 10\text{V}$ , $I_D = 13.5\text{A}$ , $T_J = 125^\circ\text{C}$			14.8	
		$V_{GS} = 4.5\text{V}$ , $I_D = 11.5\text{A}$			10.6	
Forward Transconductance	$g_{FS}$	$V_{DS} = 5\text{V}$ , $I_D = 13.5\text{A}$		75		S
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 50\text{V}$ , $f = 1\text{MHz}$		3130		pF
Output Capacitance	$C_{oss}$			245		
Reverse Transfer Capacitance	$C_{rss}$			12.5		
Gate Resistance	$R_g$	$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ , $f = 1\text{MHz}$	0.7	1.4	2.1	$\Omega$
Total Gate Charge	$Q_g(10\text{V})$	$V_{GS} = 10\text{V}$ , $V_{DS} = 50\text{V}$ , $I_D = 13.5\text{A}$		42	60	nC
Total Gate Charge	$Q_g(4.5\text{V})$			18.5	28	
Gate Source Charge	$Q_{gs}$			7.5		
Gate Drain Charge	$Q_{gd}$			4.5		
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = 10\text{V}$ , $V_{DS} = 50\text{V}$ , $R_L = 3.7\Omega$ , $R_{GEN} = 3\Omega$		8		ns
Turn-On Rise Time	$t_r$			5		
Turn-Off Delay Time	$t_{d(off)}$			41		
Turn-Off Fall Time	$t_f$			7		
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = 13.5\text{A}$ , $di/dt = 500\text{A}/\mu\text{s}$		28		nC
Body Diode Reverse Recovery Charge	$Q_{rr}$			130		
Maximum Body-Diode Continuous Current	$I_S$				4	A
Diode Forward Voltage	$V_{SD}$	$V_{GS} = 0\text{V}$ , $I_S = 1\text{A}$		0.7	1	V

## ■ Marking

Marking	K7006 KC****
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# N-Channel MOSFET

## 2KK7006

### Typical Electrical and Thermal Characteristics

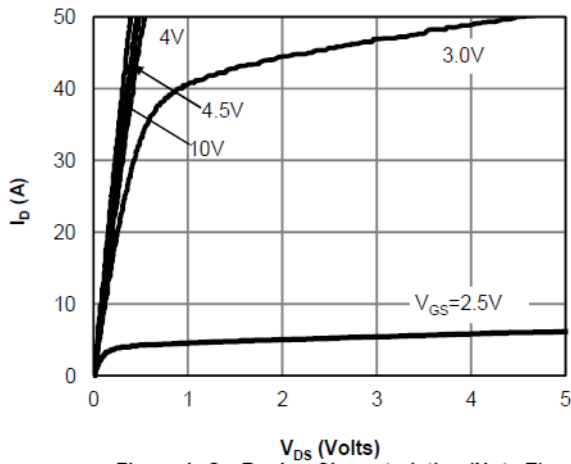


Figure 1: On-Region Characteristics (Note E)

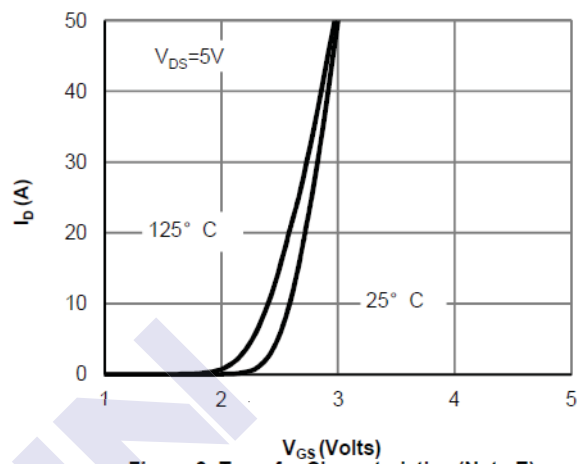


Figure 2: Transfer Characteristics (Note E)

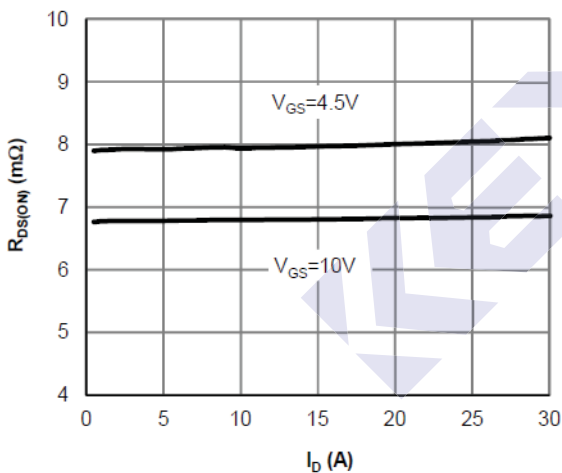


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

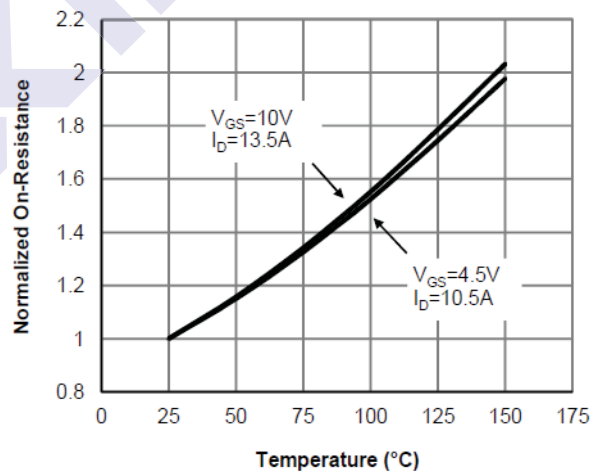


Figure 4: On-Resistance vs. Junction Temperature (Note E)

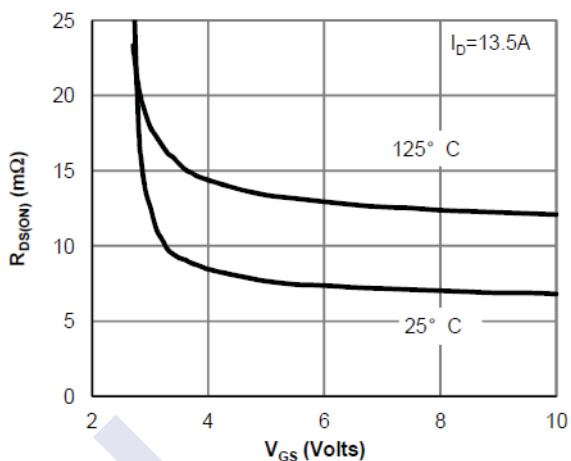


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

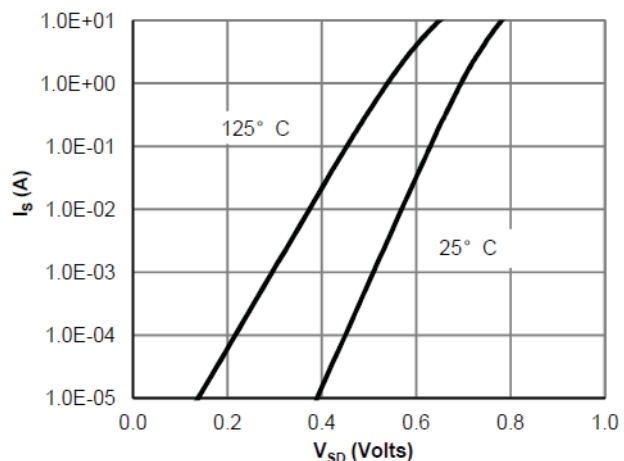


Figure 6: Body-Diode Characteristics (Note E)

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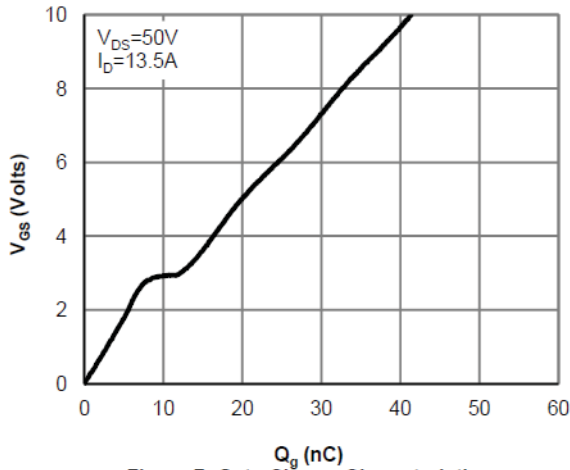


Figure 7: Gate-Charge Characteristics

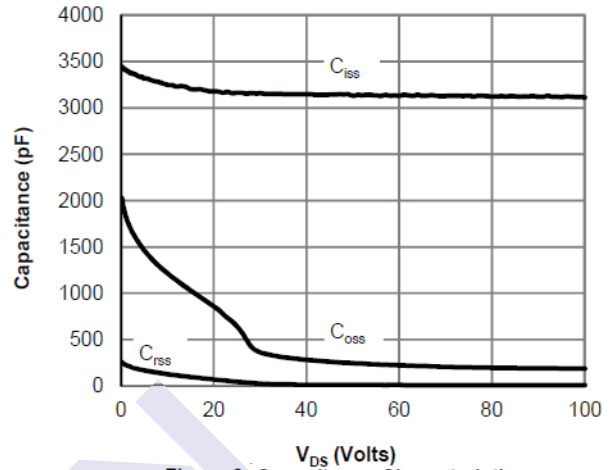


Figure 8: Capacitance Characteristics

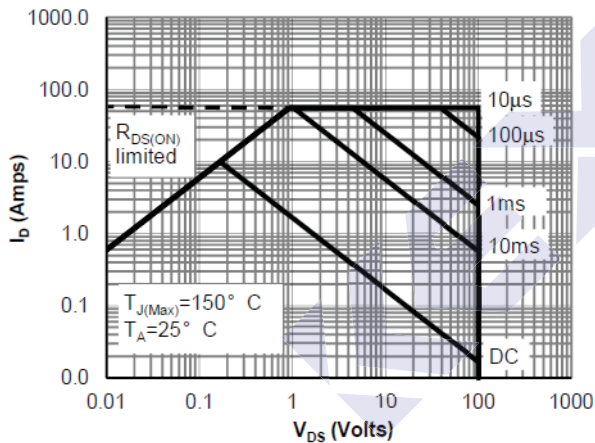


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

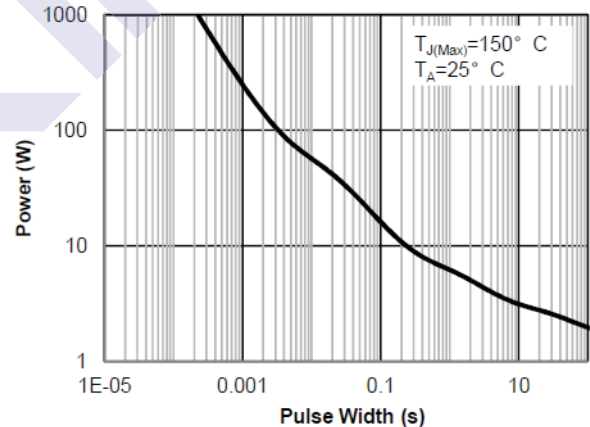


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

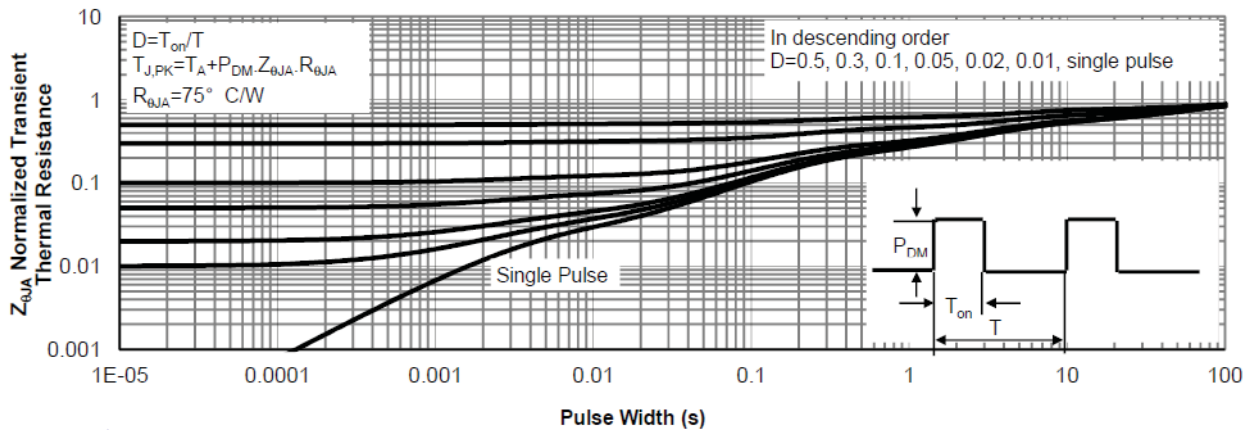


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

# N-Channel MOSFET

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Figure A: Gate Charge Test Circuit & Waveforms

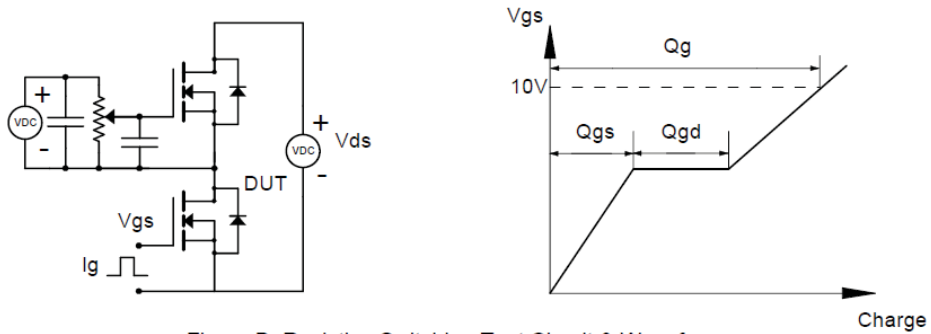


Figure B: Resistive Switching Test Circuit & Waveforms

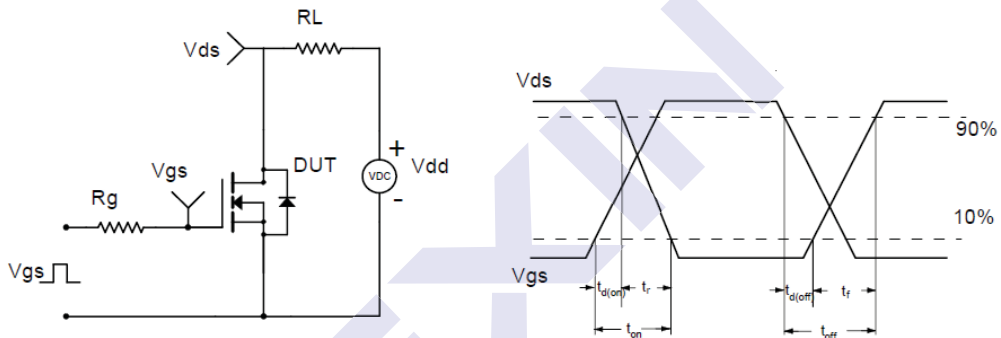


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

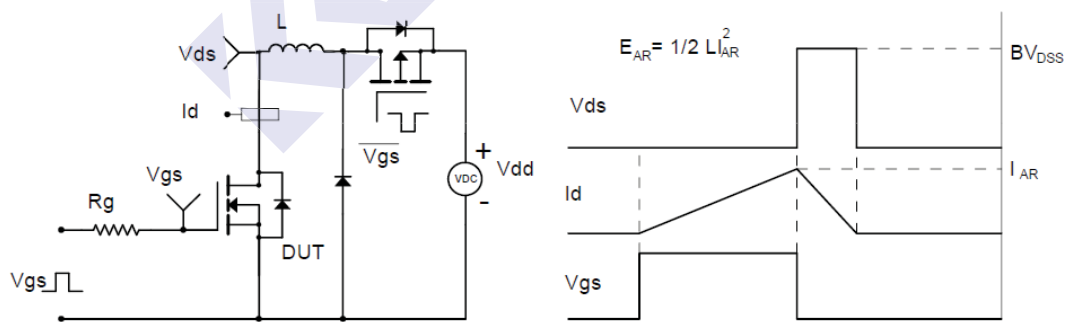


Figure D: Diode Recovery Test Circuit & Waveforms

